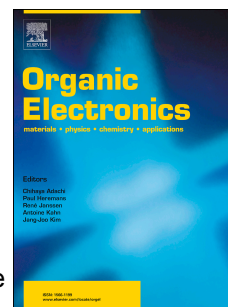


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Scanning Kelvin Probe Microscopy investigation of the contact resistances and charge mobility in n-type PDIF-CN₂ thin-film transistors

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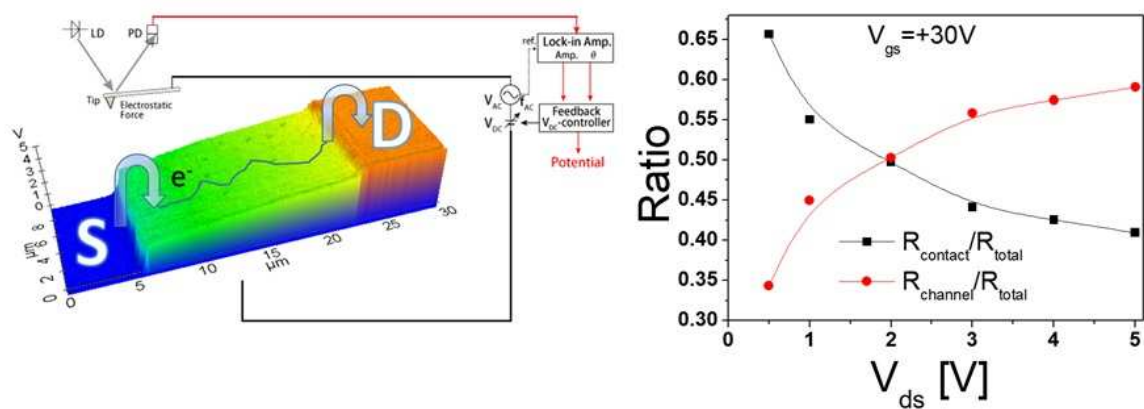
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